

**Search Notes**

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Examiner

Young J. Kim

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

1637

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference Search History - see print out		11/7/2007	YJK

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)  see enclosed for text-search strategy	11/7/2007	YJK
SEQ ID NO: 3, 4, and 12	11/7/2007	YJK